

<b>Notice of References Cited</b>		Application/Control No. 09/731,579	Applicant(s)/Patent Under Reexamination TERRENCE RILEY ET AL.	
		Examiner Carlos Ortiz-Rodriguez	Art Unit 2125	Page 1 of 1

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**NON-PATENT DOCUMENTS**

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	W	Dilhac et al., "Thermal Modeling of a Wafer in a Rapid Thermal Processor", IEEE Transactions on Semiconductor Manufacturing; Vol 8, No.4, November 1995, 432-439.
	X	Gyugyi et al., "Control of Rapid Thermal Processing: A System Theoretic Approach", IEEE Transactions on Control Systems Technology; Vol 5, No.6, November 1997, 644-653.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.